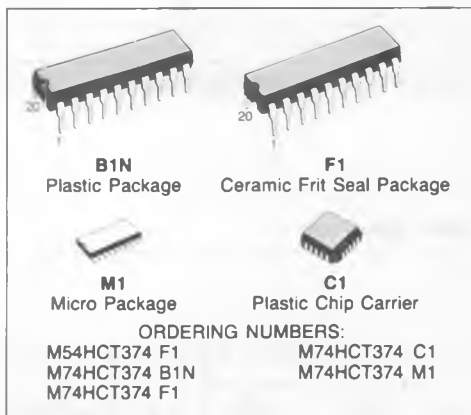


## OCTAL D-TYPE FLIP-FLOP WITH 3-STATE OUTPUT

- LOW POWER DISSIPATION  
 $I_{CC} = 4 \mu A$  (MAX.) at  $T_A = 25^\circ C$
- COMPATIBLE WITH TTL OUTPUTS  
 $V_{IH} = 2 V$  (MIN)  $V_{IL} = 0.8 V$  (MAX.)
- OUTPUT DRIVE CAPABILITY  
 15 LSTTL LOADS
- SYMMETRICAL OUTPUT IMPEDANCE  
 $|I_{OH}| = I_{OL} = 6 mA$  (MIN.)
- BALANCED PROPAGATION DELAYS  
 $t_{PLH} = t_{PHL}$
- PIN AND FUNCTION COMPATIBLE  
 WITH 54/74LS374



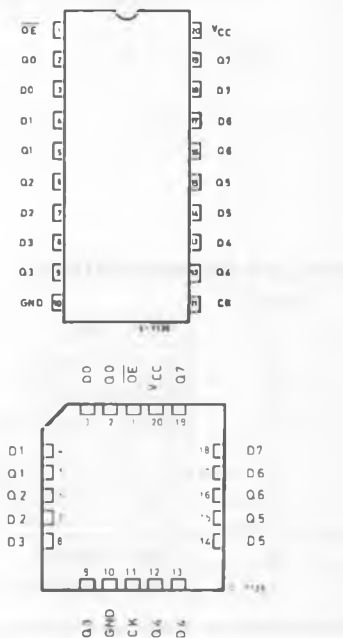
### DESCRIPTION

The M54/74HCT374 is a high speed CMOS OCTAL D-TYPE FLIP-FLOP WITH 3-STATE OUTPUT fabricated in silicon gate C<sup>2</sup>MOS technology. It has the same high speed performance of LSTTL combined with true CMOS low power consumption. This 8-bit D-type flip-flop is controlled by a clock input (CK) and an output enable input ( $\overline{OE}$ ). On the positive transition of the clock, the Q outputs will be set precisely to the logic state that was setup at the D inputs.

While the  $\overline{OE}$  input is low, the eight outputs will be in a normal logic state (high or low logic level), and while high, the outputs will be in a high impedance state. The output control does not affect the internal operation of flip-flops. That is, the old data can be retained or the new data can be entered even while the outputs are off.




The three-state output configuration and the wide choice of outline will make its application in bus-organized system simple. All inputs are equipped with protection circuits against static discharge and transient excess voltage. This integrated circuit has totally compatibility, input and output characteristic is with standard 54/74 LSTTL logic families.

### PIN CONNECTIONS (top view)



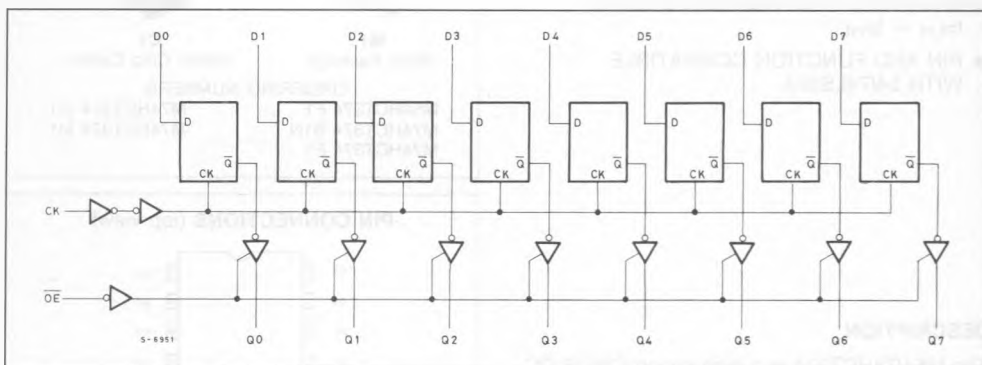
NC =  
No Internal  
Connection

### TRUTH TABLE

INPUTS			OUTPUTS
OE	CK	D	Q
H	X	X	Z
L		X	NO CHANGE
L		L	L
L		H	H

X: DON'T CARE — Z: HIGH IMPEDANCE

### LOGIC DIAGRAM



### ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
$V_{CC}$	Supply Voltage	– 0.5 to 7	V
$V_I$	DC Input Voltage	– 0.5 to $V_{CC} + 0.5$	V
$V_O$	DC Output Voltage	– 0.5 to $V_{CC} + 0.5$	V
$I_{IK}$	DC Input Diode Current	$\pm 20$	mA
$I_{OK}$	DC Output Diode Current	$\pm 20$	mA
$I_O$	DC Output Source Sink Current Per Output Pin	$\pm 35$	mA
$I_{CC}$ or $I_{GND}$	DC $V_{CC}$ or Ground Current	$\pm 70$	mA
$P_D$	Power Dissipation	500 (*)	mW
$T_{stg}$	Storage Temperature	– 65 to 150	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these condition is not implied.

(\*) 500 mW:  $\cong 65^{\circ}\text{C}$  derate to 300 mW by 10 mW/ $^{\circ}\text{C}$ :  $65^{\circ}\text{C}$  to  $85^{\circ}\text{C}$

## RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Value	Unit
$V_{CC}$	Supply Voltage	4.5 to 5.5	V
$V_I$	Input Voltage	0 to $V_{CC}$	V
$V_O$	Output Voltage	0 to $V_{CC}$	V
$T_A$	Operating Temperature 74HC Series 54HC Series	- 40 to 85 - 55 to 125	°C
$t_r, t_f$	Input Rise and Fall Time	0 to 500	ns

## DC SPECIFICATIONS

Symbol	Parameter	V <sub>CC</sub>	Test Condition		T <sub>A</sub> = 25°C 54HC and 74HC			- 40 to 85°C 74HC		- 55 to 125°C 54HC		Unit
					Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
V <sub>IH</sub>	High Level Input Voltage	4.5 to 5.5			2.0	—	—	2.0	—	2.0	—	V
V <sub>IL</sub>	Low Level Input Voltage	4.5 to 5.5			—	—	0.8	—	0.8	—	0.8	V
V <sub>OH</sub>	High Level Output Voltage	4.5	V <sub>IN</sub>	I <sub>OH</sub>	4.4	4.5	—	4.4	—	4.4	—	V
			V <sub>IH</sub> or V <sub>IL</sub>	- 20 μA								
			- 6.0 mA	4.18								
V <sub>OL</sub>	Low Level Output Voltage	4.5	V <sub>IN</sub>	I <sub>OL</sub>	—	0	0.1	—	0.1	—	0.1	V
			V <sub>IH</sub> or V <sub>IL</sub>	20 μA								
			6.0 mA	—								
I <sub>OZ</sub>	3-State Output Off-State Current	5.5	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub> V <sub>OUT</sub> = V <sub>CC</sub> or GND		—	—	± 0.5	—	± 5.0	—	± 10.0	μA
I <sub>IN</sub>	Input Leakage Current	5.5	V <sub>IN</sub> = V <sub>CC</sub> or GND		—	—	± 0.1	—	± 1	—	± 1	μA
I <sub>CC</sub>	Quiescent Supply Current	5.5	V <sub>I</sub> = V <sub>CC</sub> or GND		—	—	4	—	40	—	80	μA
I <sub>CC</sub>			Per input: V <sub>IN</sub> = 0.5V or 2.4V Other input: V <sub>CC</sub> or GND		—	—	2.0	—	2.9	—	3.0	mA

AC ELECTRICAL CHARACTERISTICS (C<sub>L</sub> = 50pF, Input t<sub>r</sub> = t<sub>f</sub> = 6ns)

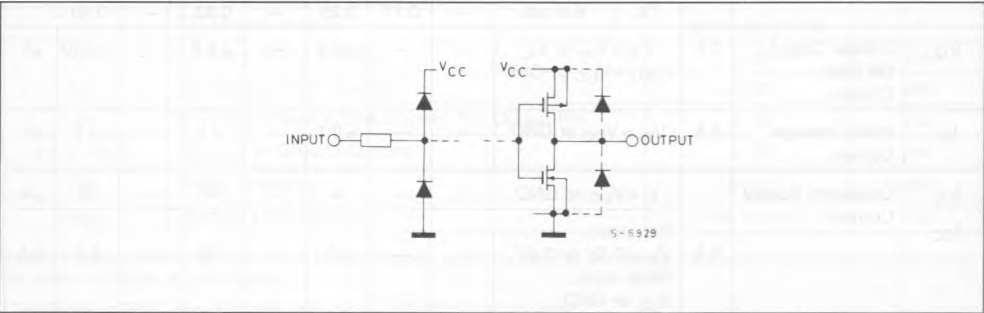
Symbol	Parameter	V <sub>CC</sub>	Test Condition	T <sub>A</sub> = 25°C 54HC and 74HC			- 40 to 85°C 74HC		- 55 to 125°C 54HC		Unit
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
t <sub>TLH</sub> t <sub>THL</sub>	Output Transition Time	4.5		—	7	12	—	15	—	18	ns
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay Time (CK-Q)	4.5		—	26	40	—	50	—	60	ns
f <sub>MAX</sub>	Maximum Clock Frequency	4.5		25	38	—	20	—	17	—	MHz
t <sub>w</sub>	Minimum Pulse Width	4.5		—	13	25	—	32	—	38	ns
t <sub>s</sub>	Minimum Set-up Time	4.5		—	6	15	—	19	—	23	ns
t <sub>h</sub>	Minimum hold Time	4.5		—	—	0	—	0	—	0	ns
t <sub>PZL</sub> t <sub>PZH</sub>	3-State Output Enable Time	4.5	R <sub>L</sub> = 1kΩ	—	27	42	—	53	—	63	ns
t <sub>PLZ</sub> t <sub>PHZ</sub>	3-State Output Disable Time	4.5	R <sub>L</sub> = 1kΩ	—	22	32	—	40	—	48	ns
C <sub>IN</sub>	Input Capacitance			—	5	10	—	10	—	10	pF
C <sub>OUT</sub>	Output Capacitance			—	10	—	—	—	—	—	pF
C <sub>PD</sub> (*)	Power Dissipation Capacitance			—	60	—	—	—	—	—	pF

Note (\*) C<sub>PD</sub> is defined as the value of IC's internal equivalent capacitance which is calculated from the operating current consumption without load. (Refer to Test Circuit)

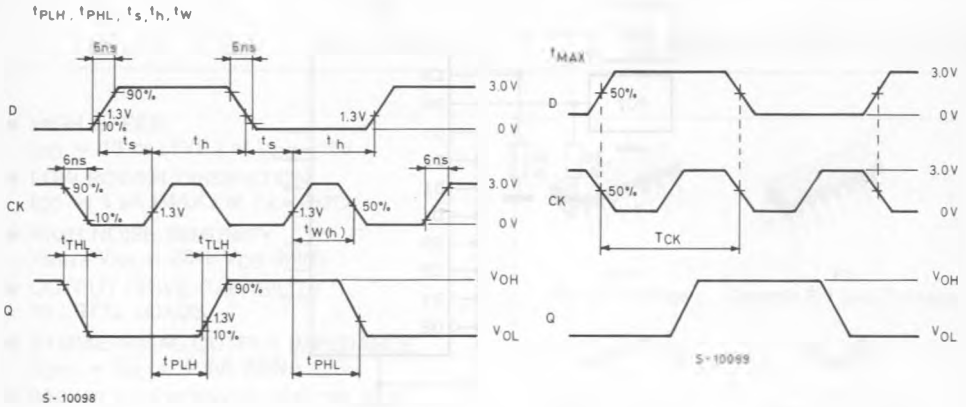
Average operating current is: I<sub>CC(opr.)</sub> = C<sub>PD</sub>•V<sub>CC</sub>•f<sub>IN</sub> + I<sub>CC</sub>/8 (per FLIP/FLOP)

And the C<sub>PD</sub> when n circuits of FLIP/FLOP operate, can be gained by the following equation. C<sub>PD</sub> (TOTAL) = 42 + 18•n (pF)

INPUT AND OUTPUT EQUIVALENT CIRCUIT



## SWITCHING CHARACTERISTICS TEST WAVEFORM



Duty cycle of CK: 50%

$$f_{MAX} = \frac{1}{T_{CK}}$$

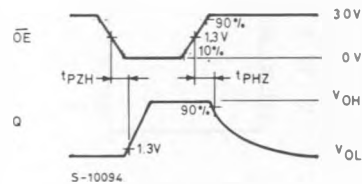
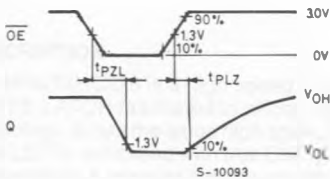
$t_{PLZ}, t_{PZL}$

The 1K $\Omega$  load resistors should be connected between outputs and V<sub>CC</sub> line and the 50pF load capacitors should be connected between outputs and GND line. All inputs except  $\overline{OE}$  input should be connected to V<sub>CC</sub> line or GND line such that outputs will be in low logic level while  $\overline{OE}$  input is held low.

$t_{PHZ}, t_{PZH}$

The 1K $\Omega$  load resistors and the 50pF load capacitors should be connected between each output and GND line.

All inputs except  $\overline{OE}$  input should be connected to V<sub>CC</sub> or GND line such that output will be in high logic level while  $\overline{OE}$  inputs is held low.



TEST CIRCUIT  $I_{CC}$  (Opr.)